# RAM Mounts Testing Summary

## RAM® Powered Dock for Honeywell RT10 Tablet

### Products Covered

RAM-HOL-HON9CLU
RAM-HOL-HON9KLU
RAM-HOL-HON9PCLU
RAM-HOL-HON9PD-DB9U
RAM-HOL-HON9PD2CLU
RAM-HOL-HON9PD2KLU
RAM-HOL-HON9PD2U
RAM-HOL-HON9PDCLU
RAM-HOL-HON9PDKL-DB9U
RAM-HOL-HON9PDKL-RJ45AU
RAM-HOL-HON9PDKLU
RAM-HOL-HON9PDU
RAM-HOL-HON9PKLU
RAM-HOL-HON9PU
RAM-HOL-HON9U

### Accompanying Power Supplies

RAM-GDS-CHARGE-V9U
RAM-GDS-CHARGE-V10-1U

| Test | Description |
|---|---|
| **Vibration – operational** | MIL-STD-810H, Method 514.8, Table 514.8C-VII, Category 4.<br>Tested performed with unlocked dock and device oriented vertical, transverse, and longitudinal. 1 hour each axis, 3 hours total. |
| **Functional Shock - operational** | MIL-STD-810H, Method 516.8, Procedure 1, 3 positive and 3 negative pulses per vertical, longitudinal, and transverse axis. 18 total pulses. Pulses are 20G, 11ms terminal peak sawtooth. |
| **Pogo Pins – Cycle rating** | Pogo pins rated to 100k cycles |
| **USB Validation Protocol, Speed, Power** | NPI Developed Testing Specification for USB 2.0 Compliance up to 480Mbps, 4.75-5.25VDC @ 900mA per port |
| **Power Supply Input Voltage Tolerance** | NPI Developed Testing Specification for Cycle Testing of Input Voltage and variable current |
| **Power Supply Output Voltage Tolerance** | NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current |
| **Power Supply Load Test** | NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current |
| **Regulatory Compliance** | FCC, IC CE, RoHS, WEEE |
| **Safety, Emission, Immunity (Ram Power Supply)** | CE EN:55032, EN 55035, IEC 61000-6-1, EN 62368-1, e-Mark |

Official NPI testing documentation. Tests performed onsite by NPI engineers.